

Application/Control No.	Applicant(s)/Patent under Reexamination		
10/506,495	MIKKELSEN ET AL.		
Examiner	Art Unit		
Patrick J. Lee	2878		

	SEAR	CHED	
Class	Subclass	Date	Examiner
250	208.1, 208.2, 370.1, 370.09	2/28/2006	PL
250	370.14	2/28/2006	PL
348	302	2/28/2006	PL
348	307-310	2/28/2006	PL

INT	INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner	

SEARCH NOT (INCLUDING SEARCH))
	DATE	EXMR
Consulted w/ S. Allen AU 2878 CL 250	2/28/2006	PL
East (see attached) - USPAT, US- PGPUB, EPO, JPO, DERWENT	2/28/2006	PL
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